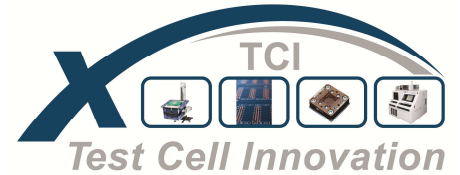


Test Cell Solution for Automotive Radar ICs



“Out-of-the-box”

guaranteed 81GHz performance at the DUT pin

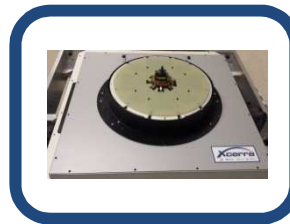
Xcerra Test Cell Innovation

Leveraging Leading Test Solutions to Address Today's and Tomorrow's Challenges

- Improve productivity beyond the limits of conventional approaches
- Improve flexibility and agility to react to fluctuating and fast ramp-up demands
- Gain competitive advantage by focusing resources on new, disruptive technologies



76-81GHz upgrade on scalable LTX-Credence X-series platform



Multitest proprietary contacting solution: mmWave



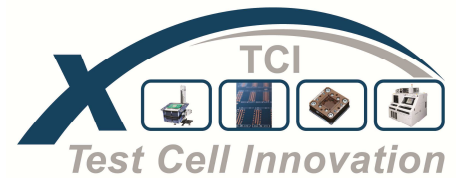
Multitest tri-temp MT9510 pick & place handler with standard conversion kit

Customer Benefits

- Guaranteed signal integrity and performance at the DUT pin
- Guaranteed electrical and tri-temp thermal performance
- In-socket calibration to validate test cell performance



Test Cell Solution for Automotive Radar ICs



Automotive Radar Complete Test Cell Solutions

Only fully integrated solution in the Industry

- At speed test of 76- 81 GHz radar signals (transmit and receive)
- All components from one supplier (test solution, loadboard, contactor and handling)

Guaranteed signal integrity

- Impedance controlled signal path from DUT to instrument
- Calibration up to the device pin

Proprietary, unique contacting solution

- Eliminates PCB interface for mmWave signals
- Production ready hybrid pogo/cantilever design

Handler supports tri-temp testing for automotive

- Insulation technique maintains temperature within +/- 2° C
- Standard conversion kit compatible with hybrid contactor design

True volume production solution offers higher ROI

- Flexible solution developed using standard & proven MX ATE, contacting, and handling instrumentation
- Reconfigurable for a range of automotive applications

Signal Path Optimization

RF Instrument ↔ Loadboard ↔ Contactor ↔ DUT

- **Design and simulation of the complete signal path**
- **Minimizes connection interfaces and maintains required 81 GHz signal quality and robustness for production**
- **Integrated interface design reduces signal transitions by factor of 3**
- **Measurements confirm simulation results: -10dB return loss @ 81GHz**

